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| | 10541897 | LEE ET AL. |
| | Examiner Nguyen, Lauren | Art Unit 2871 |

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| Class | Subclass | Date | Examiner |
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| 349 | 61-62, 64, 67, 96, 112-113 | 02/06/2007 | LN |

SEARCH NOTES

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| Consulted Primary Examiner James Reagan | 02/06/2007 | LN |
| Consulted Supervisory Patent Examiner George Nguyen | 02/07/2007 | LN |

INTERFERENCE SEARCH

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